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Crystallographic Image Processing Software for Scanning Probe Microscopists PAVEL PLACHINDA, BILL MOON, PETER MOECK, Portland State University — Following the common practice of structural electron crystallography, scanning probe microscopy (SPM) images can be processed “crystallographically” [1,2]. An estimate of the point spread function of the SPM can be obtained and subsequently its influence removed from the images. Also a difference Fourier synthesis can be calculated in order to enhance the visibility of structural defects. We are currently in the process of developing dedicated PC-based software for the wider SPM community.

[1] P. Moeck, B. Moon Jr., M. Abdel-Hafiez, and M. Hietschold, Proc. NSTI 2009, Houston, May 3-7, 2009, Vol. I (2009) 314-317, (ISBN: 978-1-4398-1782-7).

[2] P. Moeck, M. Toader, M. Abdel-Hafiez, and M. Hietschold, Proc. 2009 International Conference on Frontiers of Characterization and Metrology for Nanoelectronics, May 11-14, 2009, Albany, New York, *Best Paper Award*

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